

Notice of References Cited	Application/Control No. 10/722,267		Applicant(s)/Patent Under Reexamination O'DEA ET AL.	
	Examiner DILEK B. COBANOGLU		Art Unit 3626	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,638,436 A	01-1987	Badger et al.	607/102
*	B	US-4,722,056 A	01-1988	Roberts et al.	606/130
*	C	US-5,161,535 A	11-1992	Short et al.	600/437
*	D	US-5,603,323 A	02-1997	Pflugrath et al.	600/437
*	E	US-5,949,491 A	09-1999	Callahan et al.	348/442
*	F	US-5,999,702 A	12-1999	Brown et al.	358/1.6
*	G	US-6,196,971 B1	03-2001	Prater et al.	600/450
*	H	US-6,475,146 B1	11-2002	Frelburger et al.	600/437
*	I	US-2002/0188474 A1	12-2002	Collamore et al.	705/3
*	J	US-2002/0198454 A1	12-2002	Seward et al.	600/437
*	K	US-2003/0026464 A1	02-2003	Kamiyama et al.	382/128
*	L	US-2003/0035584 A1	02-2003	Nicolas et al.	382/232
*	M	US-6,526,163 B1	02-2003	Halmann et al.	382/128

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	google patent search 3/11/2010
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/722,267		Applicant(s)/Patent Under Reexamination O'DEA ET AL.	
	Examiner DILEK B. COBANOGLU		Art Unit 3626	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,557,102 B1	04-2003	Wong et al.	713/176
*	B	US-2003/0097065 A1	05-2003	Lee et al.	600/437
*	C	US-6,569,097 B1	05-2003	McMorrow et al.	600/437
*	D	US-6,574,499 B1	06-2003	Dines et al.	600/427
*	E	US-2003/0139665 A1	07-2003	Takayama et al.	600/407
*	F	US-2003/0167004 A1	09-2003	Dines et al.	600/437
*	G	US-2003/0195424 A1	10-2003	McMorrow et al.	600/439
*	H	US-6,656,120 B2	12-2003	Lee et al.	600/437
*	I	US-2004/0015079 A1	01-2004	Berger et al.	600/437
*	J	US-6,685,637 B1	02-2004	Rom, George Daniel	600/437
*	K	US-2004/0044666 A1	03-2004	Piehler, Michael J.	707/010
*	L	US-6,872,179 B2	03-2005	Kamiyama et al.	600/437
*	M	US-2005/0054921 A1	03-2005	Katsman et al.	600/437

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/722,267		Applicant(s)/Patent Under Reexamination O'DEA ET AL.	
	Examiner DILEK B. COBANOGLU		Art Unit 3626	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0054920 A1	03-2005	Washburn et al.	600/437
*	B	US-6,876,879 B2	04-2005	Dines et al.	600/427
*	C	US-6,911,916 B1	06-2005	Wang et al.	340/825
*	D	US-7,041,058 B2	05-2006	Piebler, Michael J.	600/437
*	E	US-7,052,459 B2	05-2006	Washburn et al.	600/437
*	F	US-7,139,417 B2	11-2006	Nicolas et al.	382/131
*	G	US-7,189,205 B2	03-2007	McMorrow et al.	600/437
*	H	US-7,457,672 B2	11-2008	Katsman et al.	700/17
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.